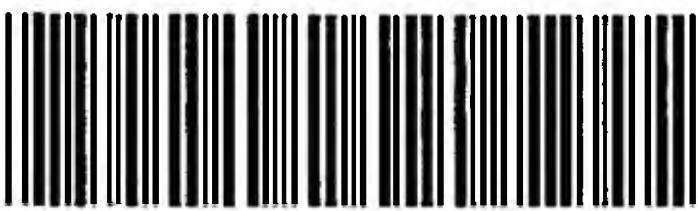


## Search Notes



**Application/Control No.**

10/604.571

---

**Examiner**

(Nancy) Thanh-Nhan P.  
Nguyen

**Applicant(s)/Patent under  
Reexamination**

CHEN ET AL.

## Art Unit

2871

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
—	as above	—	—